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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/540,389	07/20/2005	Satoshi Takei	124418	2689
25944 7	590 09/25/2006	EXAM	EXAMINER	
OLIFF & BERRIDGE, PLC P.O. BOX 19928			CHOI, LING SIU	
ALEXANDRIA			ART UNIT	PAPER NUMBER
		•	1713	
			DATE MAILED: 09/25/2000	6

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)	
	10/540,389	TAKEI ET AL.	
Office Action Summary	Examiner	Art Unit	
	Ling-Siu Choi	1713	
The MAILING DATE of this communication Period for Reply	appears on the cover sheet w	ith the correspondence address)
A SHORTENED STATUTORY PERIOD FOR REWHICHEVER IS LONGER, FROM THE MAILING Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. If NO period for reply is specified above, the maximum statutory per Failure to reply within the set or extended period for reply will, by state Any reply received by the Office later than three months after the material patent term adjustment. See 37 CFR 1.704(b).	B DATE OF THIS COMMUNI R 1.136(a). In no event, however, may a riod will apply and will expire SIX (6) MOR atute, cause the application to become A	CATION. reply be timely filed NTHS from the mailing date of this communicat BANDONED (35 U.S.C. § 133).	
Status			
1) Responsive to communication(s) filed on 23	3 June 2005.		
2a) ☐ This action is FINAL . 2b) ☒ T	his action is non-final.		
3) Since this application is in condition for allow	wance except for formal mat	ters, prosecution as to the merits	is
closed in accordance with the practice unde	er <i>Ex parte Quayl</i> e, 1935 C.D). 11, 453 O.G. 213.	
Disposition of Claims			
4)⊠ Claim(s) <u>1-13</u> is/are pending in the applicati	ion.		
4a) Of the above claim(s) is/are without	drawn from consideration.		
5) Claim(s) is/are allowed.			
6)⊠ Claim(s) <u>1-13</u> is/are rejected.			
7) Claim(s) is/are objected to.			
8) Claim(s) are subject to restriction and	d/or election requirement.		
Application Papers			
9) The specification is objected to by the Exam	iner.		
10)⊠ The drawing(s) filed on 23 June 2005 is/are:	a)⊠ accepted or b)⊡ obje	cted to by the Examiner.	
Applicant may not request that any objection to t	the drawing(s) be held in abeya	nce. See 37 CFR 1.85(a).	
Replacement drawing sheet(s) including the corn	rection is required if the drawing	(s) is objected to. See 37 CFR 1.121	(d).
11)☐ The oath or declaration is objected to by the	Examiner. Note the attache	d Office Action or form PTO-152.	
Priority under 35 U.S.C. § 119			
12)⊠ Acknowledgment is made of a claim for fore a)⊠ All b)□ Some * c)□ None of:	ign priority under 35 U.S.C. {	3 119(a)-(d) or (f).	
1. Certified copies of the priority docume	ents have been received.		
2. Certified copies of the priority docume	ents have been received in A	pplication No	
3. Copies of the certified copies of the p	•	received in this National Stage	
application from the International Burn	, , ,		
* See the attached detailed Office action for a I	list of the certified copies not	received.	
Attachment(s)			
1) X Notice of References Cited (PTO-892)	4) Interview S	Summary (PTO-413)	
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/Mail Date	
3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date <u>07/20/2005</u> .	5) \(\bigcirc \text{Notice of I} \\ 6) \(\bigcirc \text{Other:} \(\bigcirc \)	nformal Patent Application	
	. —		

DETAILED ACTION

1. Claims 1-13 are now pending, wherein claims 1-11 are drawn to a gap fill material forming composition; claim 12 is drawn to a method to form a gap fill material layer for use in manufacture of semiconductor device; claim 13 is drawn to a gap fill material layer.

Claim Objections

2. Claims 1-13 are objected to because of the following informalities: (a) Claim 1, line 1, "composition characterized in that" is suggested to be changed to --composition, wherein-- and (b) Claim 7, line 2, "the polymer is a dextrin ester compound" is suggested to be changed to --the polymer is a dextrin ester--.

Appropriate correction is required.

Claim Analysis

3. Summary of Claim 1:

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a gap fill material forming composition comprising			
Α	a polymer having a hydroxy group or a carboxy group		
В	a crosslinking agent		
whe	rein the composition is used in semiconductor device by a method comprising		
1	coating a photoresist on a substrate having a hole with aspect ratio shown in		
	height/diameter of 1 or more		
2	transferring an image to the substrate by use of lithography process		
with	the composition being coated on the substrate prior to coating of the photoresist		

Summary of Claim 13:

A gap fill material layer manufactured by		
Α	coating the gap fill material forming composition <u>according to claim 1</u> on a	
	semiconductor substrate	
В	baking it,	
in which the gap fill material layer has a dissolution rate of from 3-200 nm per second		
for an alkaline aqueous solution having a concentration of 0.1-20%		

Claim Rejections - 35 USC § 102

4. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless --

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

(e) the invention was described in a patent granted on an application for patent by another filed in the United States before the invention thereof by the applicant for patent, or on an international application by another who has fulfilled the requirements of paragraphs (1), (2), and (4) of section 371(c) of this title before the invention thereof by the applicant for patent.

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5. Claims 1-2 and 4-13 rejected under 35 U.S.C. 102(b) as being anticipated by Rutter et al. (EP 1 150 343 A2).

Rutter et al. disclose a composition comprising one or more crosslinkable polymers having a weight average molecular weight of less than or equal to about 8,000, wherein the crosslinkable polymer comprises at least one hydroxyl group containing monomer, wherein the crosslinker includes di-, tri-, tetra, or higher multifunctional ethylenically unsaturated monomer; the hydoxy group containing monomer is aliphatic or aromatic, which is vinyl phenol, vinyl cresol, vinyl methoxy phenol, hydroxyethyl (meth)acrylate, 2-hydroxypropyl (meth)acrylate, 3-hydroxypropyl (meth)acrylate, hydroxycyclohexyl (meth)acrylate, hydroxyphenyl (met)acrylate, diethyleneglycol (meth)acrylate....hydroxyethyl itaconate ([0027]; [0043]; claim 1). Rutter et al. further disclose that the composition comprises acid catalyst which includes free acid and acid generator. Rutter et al. furthermore disclose the composition provides substantially planarized surface in the manufacture of electronic devices and can function as an antireflective coating for 193 nm radiation when the composition contains aromatic group(abstract; [0062]). Thus, the present claims are anticipated by the disclosure of Rutter et al.

6. Claims 1-13 are rejected under 35 U.S.C. 102(e) as being anticipated by Takei et al. (EP 1 315 045 A1).

<u>Takei et al.</u> disclose a composition for forming a gap-filling material to be used in a semiconductor device by a method of applying the composition to the substrate with

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holes having an aspect ratio of at least 1 to planarize the surface of the substrate; then applying a resist coating onto a substrate; and finally transferring an image on the substrate using a lithographic process, wherein the composition comprises a polymer having a weight average molecular weight of 500 to 30,000, a crosslinking agent, and additives (page 3, lines 55-56; [0066]-[0069]; claims 1 and 17). Takei et al. further disclose that the polymer is poly(p-vinylphenol), poly(styrene-co-p-vinylphenol), poly(methyl methacrylate-co-p-vinylphenol), poly(2-hydroxyethyl methacrylate-co-p-vinylphenol), poly(butyl acrylate-co-p-vinylphenol), or novolac type phenol resin (Example 6; claims 11 and 13-16). Thus, the present claims are anticipated by the disclosure of Takei et al.

7. Claims 1-2 and 4-13 are rejected under 35 U.S.C. 102(e) as being anticipated by Meador et al. (US 5,919,599).

Meador et al. disclose a deep ultraviolet antireflective composition comprising (A) the reaction product of an acrylic polymer or copolymer and a deep ultraviolet light absorbing carboxylic acid or phenolic dye to produce a polymer or copolymer linked to the carboxylic acid or phenolic dye via a hydroxyester moiety or a hydroxyether moiety respectively, (B) a crosslinking agent, and (C) an acid catalyst (Fig. 1; claim 1). Thus, the present claims are anticipated by the disclosure of Meador et al.

Conclusion

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8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ling-Siu Choi whose telephone number is 571-272-

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1098.

If attempt to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Wu, can be reach on 571-272-1114.

LING-SUI CHOI PRIMARY EXAMINER

September 12, 2006